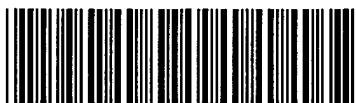


Search Notes

Application/Control No.

10/649,666

Examiner

JEAN B. FLEURANTIN

Applicant(s)/Patent under
Reexamination

AOYAMA ET AL.

Art Unit

2162

SEARCHED

Class	Subclass	Date	Examiner
707	1-10	5/13/2006	JBF
707	100-104.1	5/13/2006	JBF
707	200-206	5/13/2006	JBF
711	100	5/13/2006	JBF
715	511	5/13/2006	JBF
715	513	5/13/2006	JBF
715	526	5/13/2006	JBF
715	530	5/13/2006	JBF
715	760	5/13/2006	JBF
717	122	5/13/2006	JBF
717	170	5/13/2006	JBF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	100	5/13/2006	JBF
707	104.1 203	5/13/2006	JBF
715 717	513 170	5/13/2006	JBF

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST (US PG PUB, US PT, EPO, JPO, DERWENT AND IBM TDB)	5/13/2006	JBF
707/CCLS AND 715/CCLS and all related applications have been reviewed for possible Double Patenting	5/13/2006	JBF
NPL - ACM	5/13/2006	JBF
NPL - IEEE	5/13/2006	JBF
CONSULTED TQAS 101 HELP PANEL T. SWANN	5/15/2006	JBF